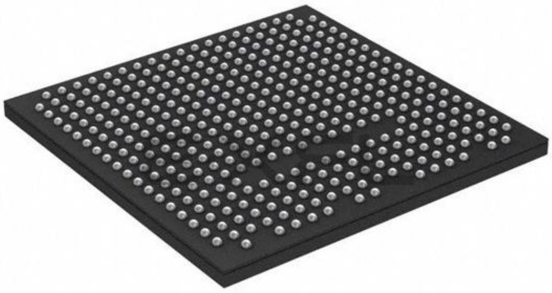
Lattice Semiconductor Corporation - LFE5U-85F-7BG381I Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Active
Number of LABs/CLBs	21000
Number of Logic Elements/Cells	84000
Total RAM Bits	3833856
Number of I/O	205
Number of Gates	-
Voltage - Supply	1.045V ~ 1.155V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	381-FBGA
Supplier Device Package	381-CABGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5u-85f-7bg381i

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Contents

1. General Description

The ECP5/ECP5-5G family of FPGA devices is optimized to deliver high performance features such as an enhanced DSP architecture, high speed SERDES (Serializer/Deserializer), and high speed source synchronous interfaces, in an economical FPGA fabric. This combination is achieved through advances in device architecture and the use of 40 nm technology making the devices suitable for high-volume, high-speed, and low-cost applications.

The ECP5/ECP5-5G device family covers look-up-table (LUT) capacity to 84K logic elements and supports up to 365 user I/Os. The ECP5/ECP5-5G device family also offers up to 156 18 x 18 multipliers and a wide range of parallel I/O standards.

The ECP5/ECP5-5G FPGA fabric is optimized high performance with low power and low cost in mind. The ECP5/ ECP5-5G devices utilize reconfigurable SRAM logic technology and provide popular building blocks such as LUT-based logic, distributed and embedded memory, Phase-Locked Loops (PLLs), Delay-Locked Loops (DLLs), pre-engineered source synchronous I/O support, enhanced sysDSP slices and advanced configuration support, including encryption and dual-boot capabilities.

The pre-engineered source synchronous logic implemented in the ECP5/ECP5-5G device family supports a broad range of interface standards including DDR2/3, LPDDR2/3, XGMII, and 7:1 LVDS.

The ECP5/ECP5-5G device family also features high speed SERDES with dedicated Physical Coding Sublayer (PCS) functions. High jitter tolerance and low transmit jitter allow the SERDES plus PCS blocks to be configured to support an array of popular data protocols including PCI Express, Ethernet (XAUI, GbE, and SGMII) and CPRI. Transmit De-emphasis with pre- and post-cursors, and Receive Equalization settings make the SERDES suitable for transmission and reception over various forms of media.

The ECP5/ECP5-5G devices also provide flexible, reliable and secure configuration options, such as dual-boot capability, bit-stream encryption, and TransFR field upgrade features.

ECP5-5G family devices have made some enhancement in the SERDES compared to ECP5UM devices. These enhancements increase the performance of the SERDES to up to 5 Gb/s data rate.

The ECP5-5G family devices are pin-to-pin compatible with the ECP5UM devices. These allows a migration path for users to port designs from ECP5UM to ECP5-5G devices to get higher performance.

The Lattice Diamond™ design software allows large complex designs to be efficiently implemented using the ECP5/ECP5-5G FPGA family. Synthesis library support for ECP5/ECP5-5G devices is available for popular logic synthesis tools. The Diamond tools use the synthesis tool output along with the constraints from its floor planning tools to place and route the design in the ECP5/ECP5-5G device. The tools extract the timing from the routing and back-annotate it into the design for timing verification.

Lattice provides many pre-engineered IP (Intellectual Property) modules for the ECP5/ECP5-5G family. By using these configurable soft core IPs as standardized blocks, designers are free to concentrate on the unique aspects of their design, increasing their productivity.

1.1. Features

- Higher Logic Density for Increased System Integration
  - 12K to 84K LUTs
  - 197 to 365 user programmable I/Os
- Embedded SERDES
  - 270 Mb/s, up to 3.2 Gb/s, SERDES interface (ECP5)
  - 270 Mb/s, up to 5.0 Gb/s, SERDES interface (ECP5-5G)
  - Supports eDP in RDR (1.62 Gb/s) and HDR (2.7 Gb/s)
  - Up to four channels per device: PCI Express, Ethernet (1GbE, SGMII, XAUI), and CPRI
- sysDSP™
  - Fully cascadable slice architecture
  - 12 to 160 slices for high performance multiply and accumulate
  - Powerful 54-bit ALU operations
  - Time Division Multiplexing MAC Sharing
  - Rounding and truncation
  - Each slice supports
    - Half 36 x 36, two 18 x 18 or four 9 x 9 multipliers
    - Advanced 18 x 36 MAC and 18 x 18 Multiply-Multiply-Accumulate (MMAC) operations
- Flexible Memory Resources
  - Up to 3.744 Mb sysMEM™ Embedded Block RAM (EBR)
  - 194K to 669K bits distributed RAM
- sysCLOCK Analog PLLs and DLLs

  - Four DLLs and four PLLs in LFE5-45 and LFE5-85; two DLLs and two PLLs in LFE5-25 and LFE5-12
- Pre-Engineered Source Synchronous I/O
  - DDR registers in I/O cells
  - Dedicated read/write levelling functionality
  - Dedicated gearing logic
  - Source synchronous standards support
    - ADC/DAC, 7:1 LVDS, XGMII
    - High Speed ADC/DAC devices
  - Dedicated DDR2/DDR3 and LPDDR2/LPDDR3 memory support with DQS logic, up to 800 Mb/s data-rate
- Programmable sysI/O™ Buffer Supports Wide Range of Interfaces
  - On-chip termination
  - LVTTL and LVCMOS 33/25/18/15/12
  - SSTL 18/15 I, II
  - HSUL12
  - LVDS, Bus-LVDS, LVPECL, RSDS, MLVDS
  - subLVDS and SLVS, MIPI D-PHY input interfaces
- Flexible Device Configuration
  - Shared bank for configuration I/Os
  - SPI boot flash interface
  - Dual-boot images supported
  - Slave SPI
  - TransFR™ I/O for simple field updates
- Single Event Upset (SEU) Mitigation Support
  - Soft Error Detect – Embedded hard macro
  - Soft Error Correction – Without stopping user operation
  - Soft Error Injection – Emulate SEU event to debug system error handling
- System Level Support
  - IEEE 1149.1 and IEEE 1532 compliant
  - Reveal Logic Analyzer
  - On-chip oscillator for initialization and general use
  - 1.1 V core power supply for ECP5, 1.2 V core power supply for ECP5UM5G

Table 1.1. ECP5 and ECP5-5G Family Selection Guide

Device	LFE5UM-25 LFE5UM5G-25	LFE5UM-45 LFE5UM5G-45	LFE5UM-85 LFE5UM5G-85	LFE5U-12	LFE5U-25	LFE5U-45	LFE5U-85
LUTs (K)	24	44	84	12	24	44	84
sysMEM Blocks (18 Kb)	56	108	208	32	56	108	208
Embedded Memory (Kb)	1,008	1944	3744	576	1,008	1944	3744
Distributed RAM Bits (Kb)	194	351	669	97	194	351	669
18 X 18 Multipliers	28	72	156	28	28	72	156
SERDES (Dual/Channels)	1/2	2/4	2/4	0	0	0	0
PLLs/DLLs	2/2	4/4	4/4	2/2	2/2	4/4	4/4
Packages (SERDES Channels / IO Count)							
256 caBGA (14 x 14 mm^2, 0.8 mm)	—	—	—	0/197	0/197	0/197	—
285 csfBGA (10 x 10 mm^2, 0.5 mm)	2/118	2/118	2/118	0/118	0/118	0/118	0/118
381 caBGA (17 x 17 mm^2, 0.8 mm)	2/197	4/203	4/205	0/197	0/197	0/203	0/205
554 caBGA (23 x 23 mm^2, 0.8 mm)	—	4/245	4/259	—	—	0/245	0/259
756 caBGA (27 x 27 mm^2, 0.8 mm)	—	—	4/365	—	—	—	0/365

2.7. DDRDLL

Every DDRDLL (master DLL block) can generate phase shift code representing the amount of delay in a delay block that corresponding to 90° phase of the reference clock input. The reference clock can be either from PLL, or input pin. This code is used in the DQSBUF block that controls a set of DQS pin groups to interface with DDR memory (slave DLL). There are two DDRDLLs that supply two sets of codes (for two different reference clock frequencies) to each side of the I/Os (at each of the corners). The DQSBUF uses this code to controls the DQS input of the DDR memory to 90° shift to clock DQs at the center of the data eye for DDR memory interface.

The code is also sent to another slave DLL, DLLDEL, that takes a clock input and generates a 90° shift clock output to drive the clocking structure. This is useful to interface edge-aligned Generic DDR, where 90° clocking needs to be created. Figure 2.10 shows DDRDLL functional diagram.

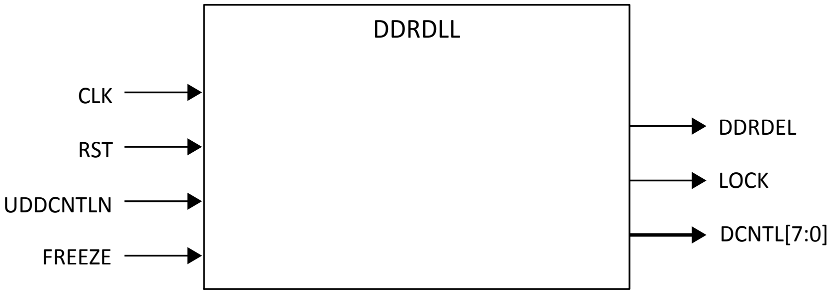


Figure 2.10. DDRDLL Functional Diagram

Table 2.5. DDRDLL Ports List

Port Name	Type	Description
CLK	Input	Reference clock input to the DDRDLL. Should run at the same frequency as the clock to the delay code.
RST	Input	Reset Input to the DDRDLL.
UDDCNTLN	Input	Update Control to update the delay code. The code is the DCNTL[7:0] outputs. These outputs are updated when the UDDCNTLN signal is LOW.
FREEZE	Input	FREEZE goes high and, without a glitch, turns off the DLL internal clock and the ring oscillator output clock. When FREEZE goes low, it turns them back on.
DDRDEL	Output	The delay codes from the DDRDLL to be used in DQSBUF or DLLDEL.
LOCK	Output	Lock output to indicate the DDRDLL has valid delay output.
DCNTL [7:0]	Output	The delay codes from the DDRDLL available for the user IP.

There are four identical DDRDLLs, one in each of the four corners in LFE5-85 and LFE5-45 devices, and two DDRDLLs in both LFE5-25 & LFE5-12 devices in the upper two corners. Each DDRDLL can generate delay code based on the reference frequency. The slave DLL (DQSBUF and DLLDEL) use the code to delay the signal, to create the phase shifted signal used for either DDR memory, to create 90° shift clock. Figure 2.11 shows the DDRDLL and the slave DLLs on the top level view.

In Figure 2.15, note that A_ALU, B_ALU and C_ALU are internal signals generated by combining bits from AA, AB, BA BB and C inputs. For further information, refer to ECP5 and ECP5-5G sysDSP Usage Guide (TN1267).

The ECP5/ECP5-5G sysDSP block supports the following basic elements.

- MULT (Multiply)
- MAC (Multiply, Accumulate)
- MULTADDSUB (Multiply, Addition/Subtraction)
- MULTADDSUBSUM (Multiply, Addition/Subtraction, Summation)

Table 2.7 shows the capabilities of each of the ECP5/ECP5-5G slices versus the above functions.

Table 2.7. Maximum Number of Elements in a Slice

Width of Multiply	x9	x18	x36
MULT	4	2	1/2
MAC	1	1	—
MULTADDSUB	2	1	—
MULTADDSUBSUM	1*	1/2	—

***Note**: One slice can implement 1/2 9x9 m9x9addsubsum and two m9x9addsubsum with two slices.

Some options are available in the four elements. The input register in all the elements can be directly loaded or can be loaded as a shift register from previous operand registers. By selecting “dynamic operation” the following operations are possible:

- In the Add/Sub option the Accumulator can be switched between addition and subtraction on every cycle.
- The loading of operands can switch between parallel and serial operations.

For further information, refer to ECP5 and ECP5-5G sysDSP Usage Guide (TN1267).

2.10. Programmable I/O Cells

The programmable logic associated with an I/O is called a PIO. The individual PIO are connected to their respective sysIO buffers and pads. On the ECP5/ECP5-5G devices, the Programmable I/O cells (PIC) are assembled into groups of four PIO cells called a Programmable I/O Cell or PIC. The PICs are placed on all four sides of the device.

On all the ECP5/ECP5-5G devices, two adjacent PIOs can be combined to provide a complementary output driver pair. All PIO pairs can implement differential receivers. Half of the PIO pairs on the left and right edges of these devices can be configured as true LVDS transmit pairs.

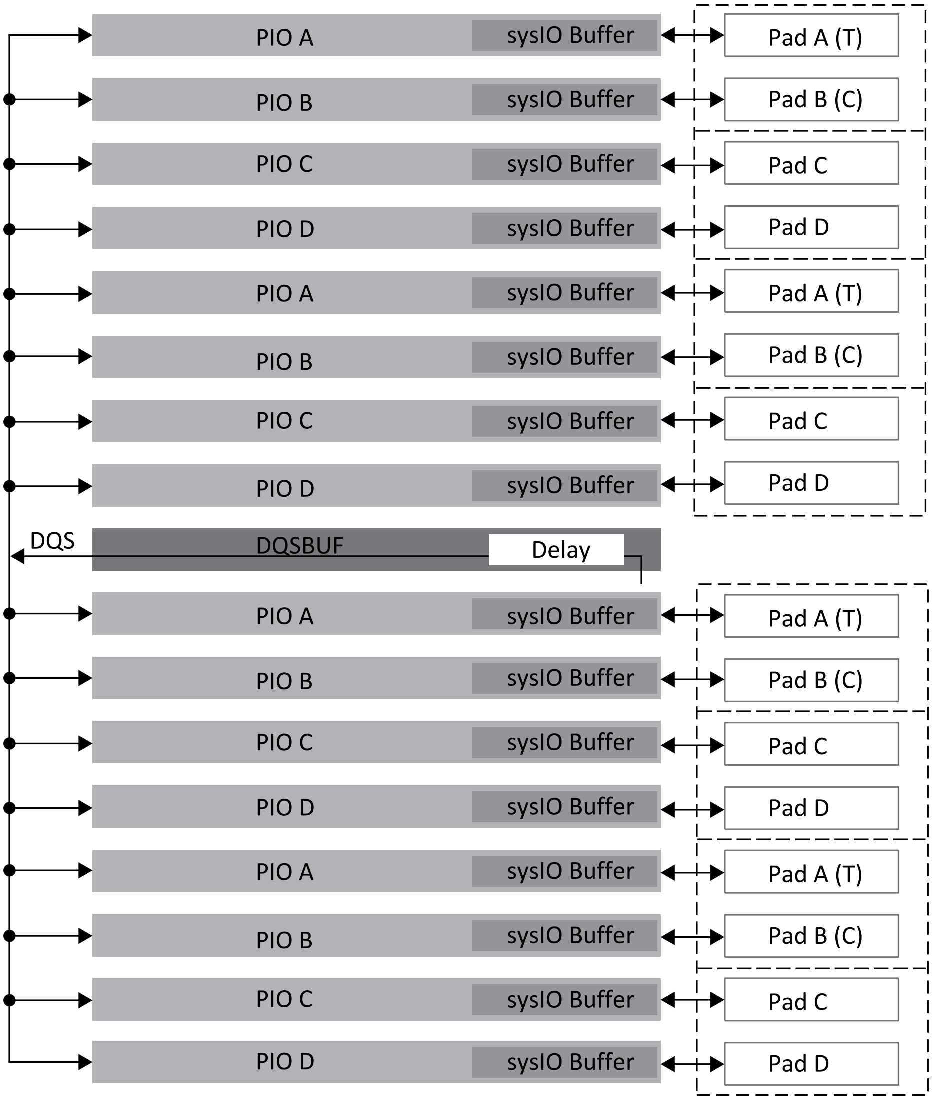


Figure 2.23. DQS Grouping on the Left and Right Edges

2.13.2. DLL Calibrated DQS Delay and Control Block (DQSBUF)

To support DDR memory interfaces (DDR2/3, LPDDR2/3), the DQS strobe signal from the memory must be used to capture the data (DQ) in the PIC registers during memory reads. This signal is output from the DDR memory device aligned to data transitions and must be time shifted before it can be used to capture data in the PIC. This time shifted is achieved by using DQSDEL programmable delay line in the DQS Delay Block (DQS read circuit). The DQSDEL is implemented as a slave delay line and works in conjunction with a master DDRDLL.

This block also includes slave delay line to generate delayed clocks used in the write side to generate DQ and DQS with correct phases within one DQS group. There is a third delay line inside this block used to provide write leveling feature for DDR write if needed.

Each of the read and write side delays can be dynamically shifted using margin control signals that can be controlled by the core logic.

FIFO Control Block shown in Figure 2.24 generates the Read and Write Pointers for the FIFO block inside the Input Register Block. These pointers are generated to control the DQS to ECLK domain crossing using the FIFO module.

2.14.4. On-Chip Programmable Termination

The ECP5/ECP5-5G devices support a variety of programmable on-chip terminations options, including:

- Dynamically switchable Single-Ended Termination with programmable resistor values of 50 Ω, 75 Ω, or 150 Ω.
- Common mode termination of 100 Ω for differential inputs.

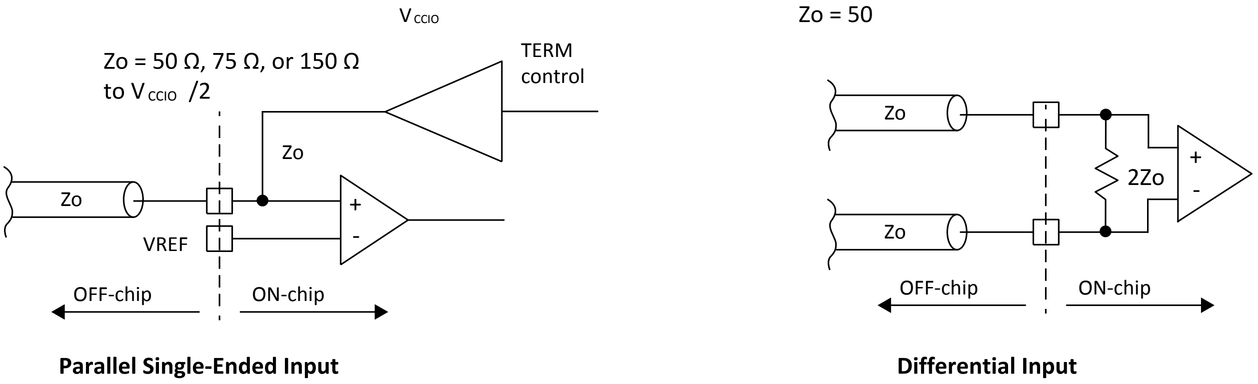


Figure 2.26. On-Chip Termination

See Table 2.12 for termination options for input modes.

Table 2.12. On-Chip Termination Options for Input Modes

IO_TYPE	Terminate to V_{CCIO}/2*	Differential Termination Resistor*
LVDS25	—	100
BLVDS25	—	100
MLVDS	—	100
LVPECL33	—	100
subLVDS	—	100
SLVS	—	100
HSUL12	50, 75, 150	—
HSUL12D	—	100
SSTL135_I / II	50, 75, 150	—
SSTL135D_I / II	—	100
SSTL15_I / II	50, 75, 150	—
SSTL15D_I / II	—	100
SSTL18_I / II	50, 75, 150	—
SSTL18D_I / II	—	100

***Notes**:

TERMINATE to V_{CCIO}/2 (Single-Ended) and DIFFRENTIAL TERMINATION RESISTOR when turned on can only have one setting per bank. Only left and right banks have this feature.

Use of TERMINATE to V_{CCIO}/2 and DIFFRENTIAL TERMINATION RESISTOR are mutually exclusive in an I/O bank. On-chip termination tolerance ±20%.

Refer to ECP5 and ECP5-5G sysIO Usage Guide (TN1262) for on-chip termination usage and value ranges.

2.14.5. Hot Socketing

ECP5/ECP5-5G devices have been carefully designed to ensure predictable behavior during power-up and power-down. During power-up and power-down sequences, the I/Os remain in tristate until the power supply voltage is high enough to ensure reliable operation. In addition, leakage into I/O pins is controlled within specified limits. See the Hot Socketing Specifications section on page 48.

Table 2.14. Available SERDES Duals per LFE5UM/LFE5UM5G Devices

Package	LFE5UM/LFE5UM5G-25	LFE5UM/LFE5UM5G-45	LFE5UM/LFE5UM5G-85
285 csfBGA	1	1	1
381 caBGA	1	2	2
554 caBGA	—	2	2
756 caBGA	—	—	2

2.15.1. SERDES Block

A SERDES receiver channel may receive the serial differential data stream, equalize the signal, perform Clock and Data Recovery (CDR) and de-serialize the data stream before passing the 8- or 10-bit data to the PCS logic. The SERDES transmitter channel may receive the parallel 8- or 10-bit data, serialize the data and transmit the serial bit stream through the differential drivers. Figure 2.28 shows a single-channel SERDES/PCS block. Each SERDES channel provides a recovered clock and a SERDES transmit clock to the PCS block and to the FPGA core logic.

Each transmit channel, receiver channel, and SERDES PLL shares the same power supply (VCCA). The output and input buffers of each channel have their own independent power supplies (VCCHTX and VCCHRX).

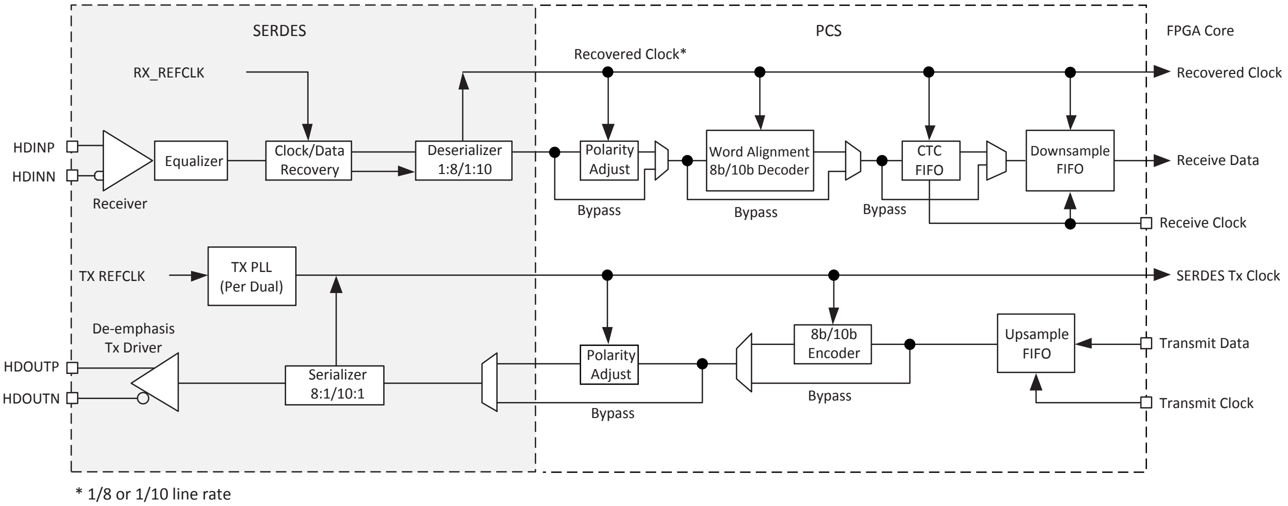


Figure 2.28. Simplified Channel Block Diagram for SERDES/PCS Block

2.15.2. PCS

As shown in Figure 2.28, the PCS receives the parallel digital data from the deserializer and selects the polarity, performs word alignment, decodes (8b/10b), provides Clock Tolerance Compensation and transfers the clock domain from the recovered clock to the FPGA clock via the Down Sample FIFO.

For the transmit channel, the PCS block receives the parallel data from the FPGA core, encodes it with 8b/10b, selects the polarity and passes the 8/10 bit data to the transmit SERDES channel.

The PCS also provides bypass modes that allow a direct 8-bit or 10-bit interface from the SERDES to the FPGA logic. The PCS interface to the FPGA can also be programmed to run at 1/2 speed for a 16-bit or 20-bit interface to the FPGA logic.

Some of the enhancements in LFE5UM/LFE5UM5G SERDES/PCS include:

- Higher clock/channel granularity: Dual channel architecture provides more clock resource per channel.
- Enhanced Tx de-emphasis: Programmable pre- and post-cursors improves Tx output signaling
- Bit-slip function in PCS: Improves logic needed to perform Word Alignment function

Refer to ECP5 and ECP5-5G SERDES/PCS Usage Guide (TN1261) for more information.

When an error is detected, and the user's error handling software determines the error did not create any risk to the system operation, the SEC tool allows the device to be re-configured in the background to correct the affected bit. This operation allows the user functions to continue to operate without stopping the system function.

Additional SEI tool is also available in the Diamond Software, by creating a frame of data to be programmed into the device in the background with one bit changed, without stopping the user functions on the device. This emulates an SEU situation, allowing the user to test and monitor its error handling software.

For further information on SED support, refer to LatticeECP3, ECP5 and ECP5-5G Soft Error Detection (SED)/Correction (SEC) Usage Guide (TN1184).

2.18.3. On-Chip Oscillator

Every ECP5/ECP5-5G device has an internal CMOS oscillator which is used to derive a Master Clock (MCLK) for configuration. The oscillator and the MCLK run continuously and are available to user logic after configuration is completed. The software default value of the MCLK is nominally 2.4 MHz. Table 2.16 lists all the available MCLK frequencies. When a different Master Clock is selected during the design process, the following sequence takes place:

1. Device powers up with a nominal Master Clock frequency of 2.4 MHz.
2. During configuration, users select a different master clock frequency.
3. The Master Clock frequency changes to the selected frequency once the clock configuration bits are received.
4. If the user does not select a master clock frequency, then the configuration bitstream defaults to the MCLK frequency of 2.4 MHz.

This internal oscillator is available to the user by routing it as an input clock to the clock tree. For further information on the use of this oscillator for configuration or user mode, refer to ECP5 and ECP5-5G sysCONFIG Usage Guide (TN1260) and ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide (TN1263).

Table 2.16. Selectable Master Clock (MCLK) Frequencies during Configuration (Nominal)

MCLK Frequency (MHz)
2.4
4.8
9.7
19.4
38.8
62

2.19. Density Shifting

The ECP5/ECP5-5G family is designed to ensure that different density devices in the same family and in the same package have the same pinout. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likelihood of success in each case. An example is that some user I/Os may become No Connects in smaller devices in the same package. Refer to the ECP5/ECP5-5G Pin Migration Tables and Diamond software for specific restrictions and limitations.

3.3. Power Supply Ramp Rates

Table 3.3. Power Supply Ramp Rates

Symbol	Parameter	Min	Typ	Max	Unit
t_{RAMP}	Power Supply ramp rates for all supplies	0.01	—	10	V/ms

Note: Assumes monotonic ramp rates.

3.4. Power-On-Reset Voltage Levels

Table 3.4. Power-On-Reset Voltage Levels

Symbol	Parameter			Min	Typ	Max	Unit
V_{PORUP}	All Devices	Power-On-Reset ramp-up trip point (Monitoring V_{CC}, V_{CCAUX}, and V_{CCIO8})	V_{CC}	0.90	—	1.00	V
			V_{CCAUX}	2.00	—	2.20	V
			V_{CCIO8}	0.95	—	1.06	V
V_{PORDN}	All Devices	Power-On-Reset ramp-down trip point (Monitoring V_{CC}, and V_{CCAUX}	V_{CC}	0.77	—	0.87	V
			V_{CCAUX}	1.80	—	2.00	V

Notes:

- These POR trip points are only provided for guidance. Device operation is only characterized for power supply voltages specified under recommended operating conditions.
- Only V_{CCIO8} has a Power-On-Reset ramp up trip point. All other V_{CCIOs} do not have Power-On-Reset ramp up detection.
- V_{CCIO8} does not have a Power-On-Reset ramp down detection. V_{CCIO8} must remain within the Recommended Operating Conditions to ensure proper operation.

3.5. Power up Sequence

Power-On-Reset (POR) puts the ECP5/ECP5-5G device in a reset state. POR is released when V_{CC}, V_{CCAUX}, and V_{CCIO8} are ramped above the V_{PORUP} voltage, as specified above.

V_{CCIO8} controls the voltage on the configuration I/O pins. If the ECP5/ECP5-5G device is using Master SPI mode to download configuration data from external SPI Flash, it is required to ramp V_{CCIO8} above V_{IH} of the external SPI Flash, before at least one of the other two supplies (V_{CC} and/or V_{CCAUX}) is ramped to V_{PORUP} voltage level. If the system cannot meet this power up sequence requirement, and requires the V_{CCIO8} to be ramped last, then the system must keep either PROGRAMN or INITN pin LOW during power up, until V_{CCIO8} reaches V_{IH} of the external SPI Flash. This ensures the signals driven out on the configuration pins to the external SPI Flash meet the V_{IH} voltage requirement of the SPI Flash.

For LFE5UM/LFE5UM5G devices, it is required to power up V_{CCA}, before V_{CCAUXA} is powered up.

3.6. Hot Socketing Specifications

Table 3.5. Hot Socketing Specifications

Symbol	Parameter	Condition	Min	Typ	Max	Unit
IDK_HS	Input or I/O Leakage Current for Top and Bottom Banks Only	$0 \leq V_{IN} \leq V_{IH}$ (Max)	—	—	±1	mA
IDK	Input or I/O Leakage Current for Left and Right Banks Only	$0 \leq V_{IN} < V_{CCIO}$	—	—	±1	mA
		$V_{CCIO} \leq V_{IN} \leq V_{CCIO} + 0.5$ V	—	18	—	mA

Notes:

1. V_{CC}, V_{CCAUX} and V_{CCIO} should rise/fall monotonically.
2. I_{DK} is additive to I_{PU}, I_{PW} or I_{BH}.
3. LVCMOS and LVTTL only.
4. Hot socket specification defines when the hot socketed device's junction temperature is at 85 °C or below. When the hot socketed device's junction temperature is above 85 °C, the I_{DK} current can exceed ±1 mA.

3.11. SERDES Power Supply Requirements[1,2,3]

Over recommended operating conditions.

Table 3.9. ECP5UM

Symbol	Description	Typ	Max	Unit
Standby (Power Down)				
$I_{CCA\text{-}SB}$	V_{CCA} Power Supply Current (Per Channel)	4	9.5	mA
$I_{CCHRX\text{-}SB}$[4]	V_{CCHRX}, Input Buffer Current (Per Channel)	—	0.1	mA
$I_{CCHTX\text{-}SB}$	V_{CCHTX}, Output Buffer Current (Per Channel)	—	0.9	mA
Operating (Data Rate = 3.125 Gb/s)				
$I_{CCA\text{-}OP}$	V_{CCA} Power Supply Current (Per Channel)	43	54	mA
$I_{CCHRX\text{-}OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX\text{-}OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 2.5 Gb/s)				
$I_{CCA\text{-}OP}$	V_{CCA} Power Supply Current (Per Channel)	40	50	mA
$I_{CCHRX\text{-}OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX\text{-}OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 1.25 Gb/s)				
$I_{CCA\text{-}OP}$	V_{CCA} Power Supply Current (Per Channel)	34	43	mA
$I_{CCHRX\text{-}OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX\text{-}OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 270 Mb/s)				
$I_{CCA\text{-}OP}$	V_{CCA} Power Supply Current (Per Channel)	28	38	mA
$I_{CCHRX\text{-}OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX\text{-}OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	8	10	mA

Notes:

1. Rx Equalization enabled, Tx De-emphasis (pre-cursor and post-cursor) disabled
2. Per Channel current is calculated with both channels on in a Dual, and divide current by two. If only one channel is on, current will be higher.
3. To calculate with Tx De-emphasis enabled, use the Diamond Power Calculator tool.
4. For $I_{CCHRX\text{-}SB}$, during Standby, input termination on Rx are disabled.
5. For $I_{CCHRX\text{-}OP}$, during operational, the max specified when external AC coupling is used. If externally DC coupled, the power is based on current pulled down by external driver when the input is driven to LOW.

Table 3.10. ECP5-5G

Symbol	Description	Typ	Max	Unit
Standby (Power Down)				
I_{CCA-SB}	V_{CCA} Power Supply Current (Per Channel)	4	9.5	mA
$I_{CCHRX-SB}$[4]	V_{CCHRX}, Input Buffer Current (Per Channel)	—	0.1	mA
$I_{CCHTX-SB}$	V_{CCHTX}, Output Buffer Current (Per Channel)	—	0.9	mA
Operating (Data Rate = 5 Gb/s)				
I_{CCA-OP}	V_{CCA} Power Supply Current (Per Channel)	58	67	mA
$I_{CCHRX-OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX-OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 3.2 Gb/s)				
I_{CCA-OP}	V_{CCA} Power Supply Current (Per Channel)	48	57	mA
$I_{CCHRX-OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX-OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 2.5 Gb/s)				
I_{CCA-OP}	V_{CCA} Power Supply Current (Per Channel)	44	53	mA
$I_{CCHRX-OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX-OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 1.25 Gb/s)				
I_{CCA-OP}	V_{CCA} Power Supply Current (Per Channel)	36	46	mA
$I_{CCHRX-OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX-OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 270 Mb/s)				
I_{CCA-OP}	V_{CCA} Power Supply Current (Per Channel)	30	40	mA
$I_{CCHRX-OP}$[5]	V_{CCHRX}, Input Buffer Current (Per Channel)	0.4	0.5	mA
$I_{CCHTX-OP}$	V_{CCHTX}, Output Buffer Current (Per Channel)	8	10	mA

Notes:

1. Rx Equalization enabled, Tx De-emphasis (pre-cursor and post-cursor) disabled
2. Per Channel current is calculated with both channels on in a Dual, and divide current by two. If only one channel is on, current will be higher.
3. To calculate with Tx De-emphasis enabled, use the Diamond Power Calculator tool.
4. For $I_{CCHRX-SB}$, during Standby, input termination on Rx are disabled.
5. For $I_{CCHRX-OP}$, during operational, the max specified when external AC coupling is used. If externally DC coupled, the power is based on current pulled down by external driver when the input is driven to LOW.

3.14.4. LVDS25E

The top and bottom sides of ECP5/ECP5-5G devices support LVDS outputs via emulated complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The scheme shown in Figure 3.1 is one possible solution for point-to-point signals.

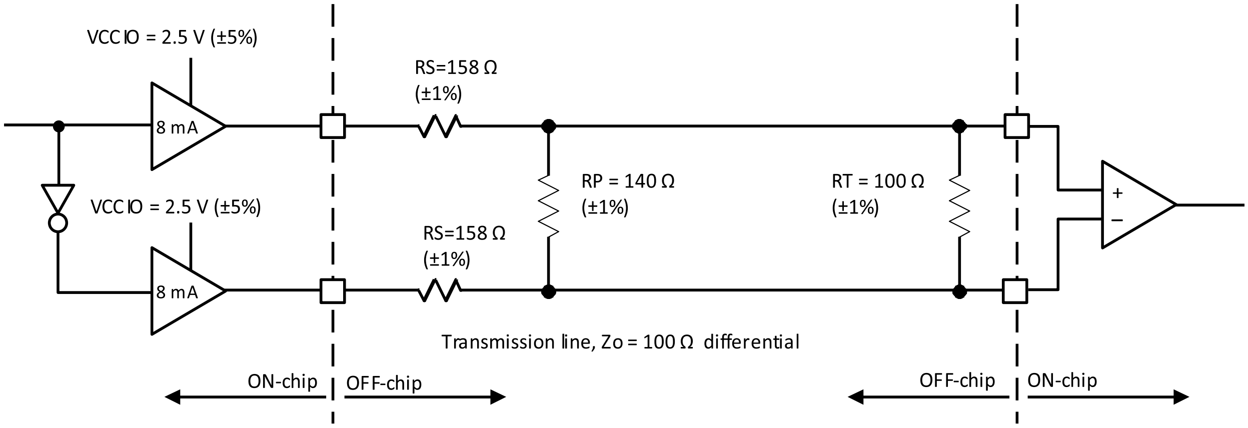


Figure 3.1. LVDS25E Output Termination Example

Table 3.14. LVDS25E DC Conditions

Parameter	Description	Typical	Unit
V_{CCIO}	Output Driver Supply (±5%)	2.50	V
Z_{OUT}	Driver Impedance	20	Ω
R_S	Driver Series Resistor (±1%)	158	Ω
R_P	Driver Parallel Resistor (±1%)	140	Ω
R_T	Receiver Termination (±1%)	100	Ω
V_{OH}	Output High Voltage	1.43	V
V_{OL}	Output Low Voltage	1.07	V
V_{OD}	Output Differential Voltage	0.35	V
V_{CM}	Output Common Mode Voltage	1.25	V
Z_{BACK}	Back Impedance	100.5	Ω
I_{DC}	DC Output Current	6.03	mA

Note: For input buffer, see LVDS Table 3.13 on page 55.

3.14.7. MLVDS25

The ECP5/ECP5-5G devices support the differential MLVDS standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The MLVDS input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3.4 is one possible solution for MLVDS standard implementation. Resistor values in the figure are industry standard values for 1% resistors.

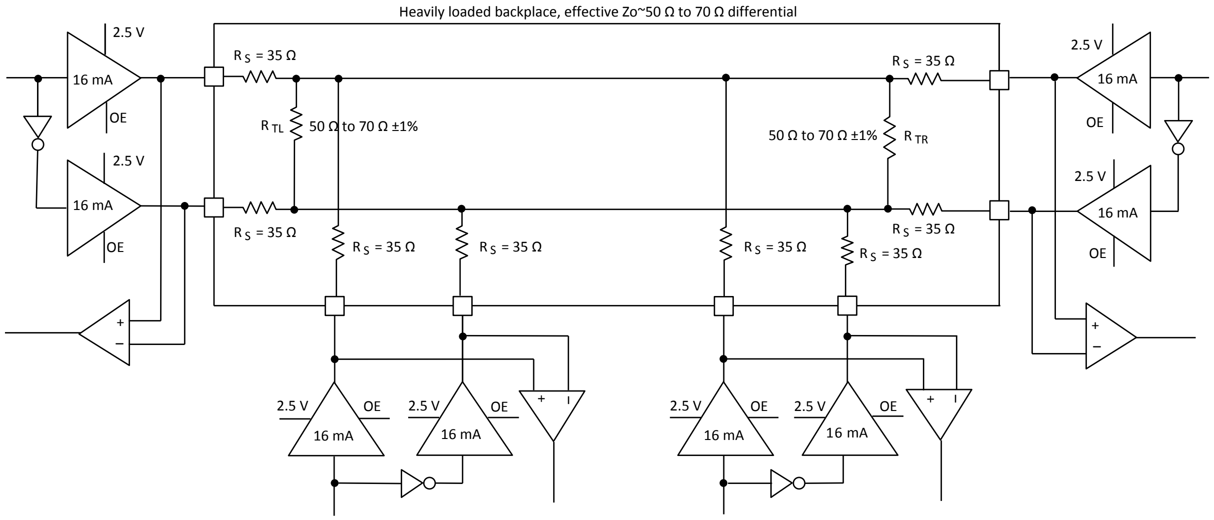


Figure 3.4. MLVDS25 (Multipoint Low Voltage Differential Signaling)

Table 3.17. MLVDS25 DC Conditions

Parameter	Description	Typical		Unit
		Zo=50 Ω	Zo=70 Ω	
V_{CCIO}	Output Driver Supply (±5%)	2.50	2.50	V
Z_{OUT}	Driver Impedance	10.00	10.00	Ω
R_S	Driver Series Resistor (±1%)	35.00	35.00	Ω
R_{TL}	Driver Parallel Resistor (±1%)	50.00	70.00	Ω
R_{TR}	Receiver Termination (±1%)	50.00	70.00	Ω
V_{OH}	Output High Voltage	1.52	1.60	V
V_{OL}	Output Low Voltage	0.98	0.90	V
V_{OD}	Output Differential Voltage	0.54	0.70	V
V_{CM}	Output Common Mode Voltage	1.25	1.25	V
I_{DC}	DC Output Current	21.74	20.00	mA

Note: For input buffer, see LVDS Table 3.13 on page 55.

Table 3.20. Register-to-Register Performance

Function	–8 Timing	Unit
Basic Functions		
16-Bit Decoder	441	MHz
32-Bit Decoder	441	MHz
64-Bit Decoder	332	MHz
4:1 Mux	441	MHz
8:1 Mux	441	MHz
16:1 Mux	441	MHz
32:1 Mux	441	MHz
8-Bit Adder	441	MHz
16-Bit Adder	441	MHz
64-Bit Adder	441	MHz
16-Bit Counter	384	MHz
32-Bit Counter	317	MHz
64-Bit Counter	263	MHz
64-Bit Accumulator	288	MHz
Embedded Memory Functions		
1024x18 True-Dual Port RAM (Write Through or Normal), with EBR Output Registers	272	MHz
1024x18 True-Dual Port RAM (Read-Before-Write), with EBR Output Registers	214	MHz
Distributed Memory Functions		
16 x 2 Pseudo-Dual Port or 16 x 4 Single Port RAM (One PFU)	441	MHz
16 x 4 Pseudo-Dual Port (Two PFUs)	441	MHz
DSP Functions		
9 x 9 Multiplier (All Registers)	225	MHz
18 x 18 Multiplier (All Registers)	225	MHz
36 x 36 Multiplier (All Registers)	225	MHz
18 x 18 Multiply-Add/Sub (All Registers)	225	MHz
18 x 18 Multiply/Accumulate (Input and Output Registers)	225	MHz

Notes:

1. These functions were generated using Lattice Diamond design software tool. Exact performance may vary with the device and the design software tool version. The design software tool uses internal parameters that have been characterized but are not tested on every device.
2. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from Lattice Diamond design software tool.

3.16. Derating Timing Tables

Logic timing provided in the following sections of this data sheet and the Diamond design tools are worst case numbers in the operating range. Actual delays at nominal temperature and voltage for best case process, can be much better than the values given in the tables. The Diamond design tool can provide logic timing numbers at a particular temperature and voltage.

Table 3.42. ECP5/ECP5-5G sysCONFIG Port Timing Specifications *(Continued)*

Symbol	Parameter		Min	Max	Unit
Slave Parallel					
f_{CCLK}	CCLK input clock frequency	—	—	50	MHz
t_{BSCH}	CCLK input clock pulsewidth HIGH	—	6	—	ns
t_{BSCL}	CCLK input clock pulsewidth LOW	—	6	—	ns
t_{CORD}	CCLK to DOUT for Read Data	—	—	12	ns
t_{SUCBDI}	Data Setup Time to CCLK	—	1.5	—	ns
t_{HCBDI}	Data Hold Time to CCLK	—	1.5	—	ns
t_{SUCS}	CSN, CSN1 Setup Time to CCLK	—	2.5	—	ns
t_{HCS}	CSN, CSN1 Hold Time to CCLK	—	1.5	—	ns
t_{SUWD}	WRITEN Setup Time to CCLK	—	45	—	ns
t_{HCWD}	WRITEN Hold Time to CCLK	—	2	—	ns
t_{DCB}	CCLK to BUSY Delay Time	—	—	12	ns

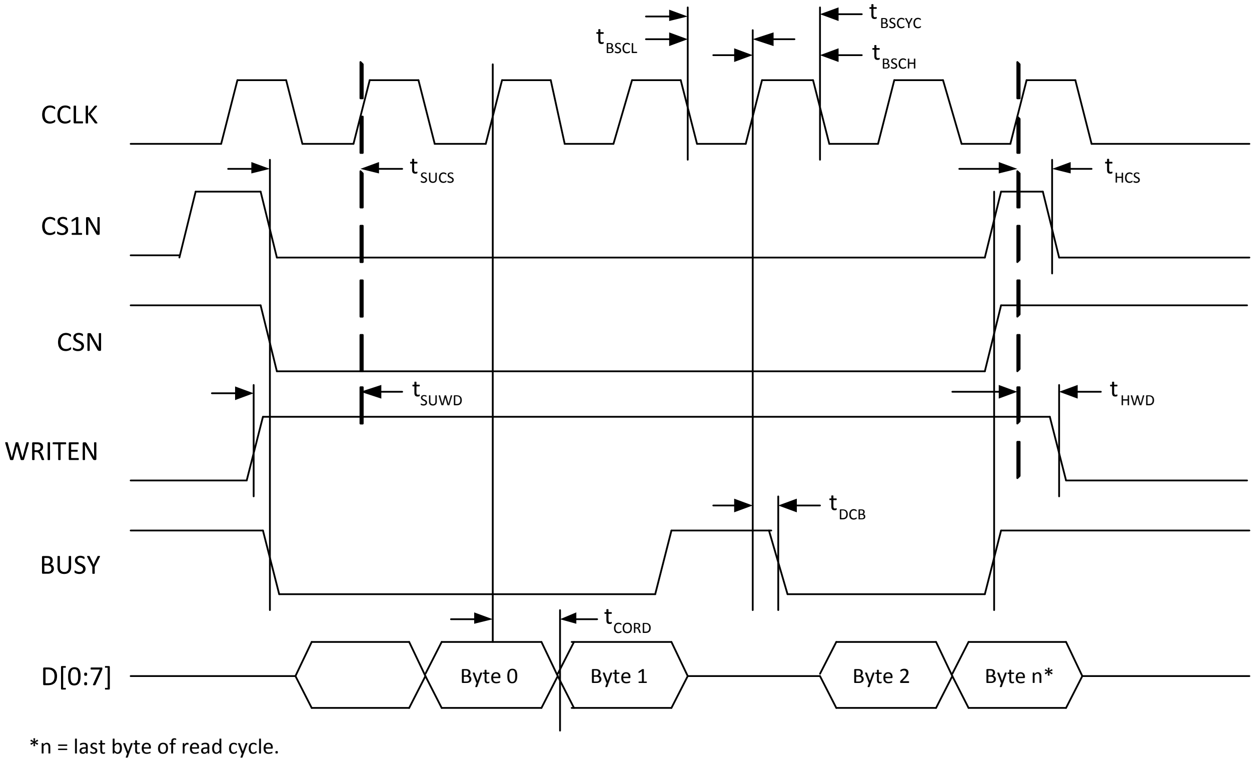


Figure 3.15. sysCONFIG Parallel Port Read Cycle

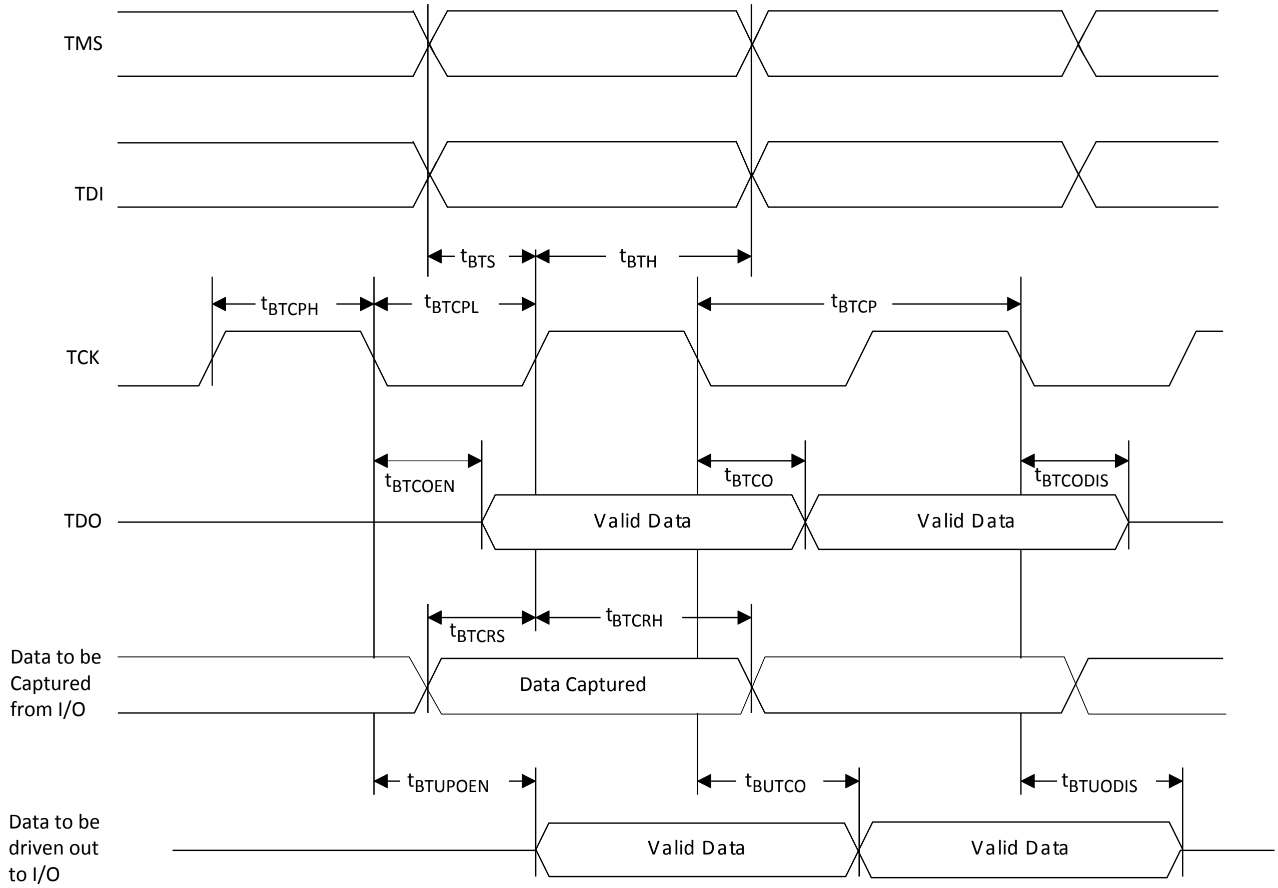
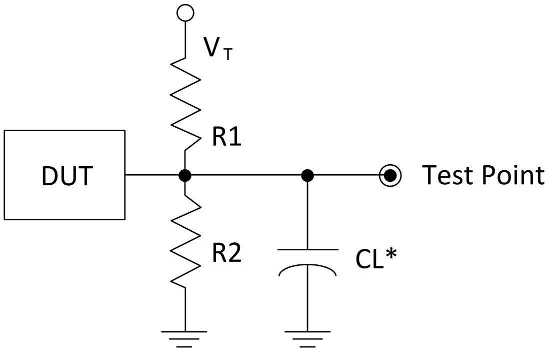


Figure 3.23. JTAG Port Timing Waveforms

3.33. Switching Test Conditions

Figure 3.24 shows the output test load that is used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are listed in Table 3.44.



*CL Includes Test Fixture and Probe Capacitance

Figure 3.24. Output Test Load, LVTTL and LVCMOS Standards

Table 3.44. Test Fixture Required Components, Non-Terminated Interfaces

Test Condition	R_1	R_2	C_L	Timing Ref.	V_T
LVTTL and other LVCMOS settings (L ≥ H, H ≥ L)	∞	∞	0 pF	LVCMOS 3.3 = 1.5 V	—
				LVCMOS 2.5 = $V_{CCIO}/2$	—
				LVCMOS 1.8 = $V_{CCIO}/2$	—
				LVCMOS 1.5 = $V_{CCIO}/2$	—
				LVCMOS 1.2 = $V_{CCIO}/2$	—
LVCMOS 2.5 I/O (Z ≥ H)	∞	1 MΩ	0 pF	$V_{CCIO}/2$	—
LVCMOS 2.5 I/O (Z ≥ L)	1 MΩ	∞	0 pF	$V_{CCIO}/2$	V_{CCIO}
LVCMOS 2.5 I/O (H ≥ Z)	∞	100	0 pF	$V_{OH} – 0.10$	—
LVCMOS 2.5 I/O (L ≥ Z)	100	∞	0 pF	$V_{OL} + 0.10$	V_{CCIO}

Note: Output test conditions for all other interfaces are determined by the respective standards.

Signal Name	I/O	Description
Configuration Pads (Used during sysCONFIG) *(Continued)*		
D1/MISO/IO1	I/O	Parallel configuration I/O. Open drain during configuration. When in SPI modes, it is an input in Master mode, and output in Slave mode. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
D2/IO2	I/O	Parallel configuration I/O. Open drain during configuration. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
D3/IO3	I/O	Parallel configuration I/O. Open drain during configuration. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
D4/IO4	I/O	Parallel configuration I/O. Open drain during configuration. This is a shared I/ O pin. When not in configuration, it can be used as general purpose I/O pin.
D5/IO5	I/O	Parallel configuration I/O. Open drain during configuration. This is a shared I/ O pin. When not in configuration, it can be used as general purpose I/O pin.
D6/IO6	I/O	Parallel configuration I/O. Open drain during configuration. When in SPI modes, it is an output in Master mode, and input in Slave mode. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
D7/IO7	I/O	Parallel configuration I/O. Open drain during configuration. When in SPI modes, it is an output in Master mode, and input in Slave mode. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin
SERDES Function		
VCCAx	—	SERDES, transmit, receive, PLL and reference clock buffer power supply for SERDES Dual x. All VCCA supply pins must always be powered to the recommended operating voltage range. If no SERDES channels are used, connect VCCA to VCC. VCCAx = 1.1 V for ECP5, VCCAx = 1.2 V for ECP5-5G.
VCCAUXAx	—	SERDES Aux Power Supply pin for SERDES Dual x. VCCAUXAx = 2.5 V.
HDRX[P/N]_D[dual_num]CH[chan_num]	I	High-speed SERDES inputs, P = Positive, N = Negative, dual_num = [0, 1], chan_num = [0, 1]. These are dedicated SERDES input pins.
HDTX[P/N]_D[dual_num]CH[chan_num]	O	High-speed SERDES outputs, P = Positive, N = Negative, dual_num = [0, 1], chan_num = [0, 1]. These are dedicated SERDES output pins.
REFCLK[P/N]_D[dual_num]	I	SERDES Reference Clock inputs, P = Positive, N = Negative, dual_num = [0, 1]. These are dedicated SERDES input pins.
VCCHRX_D[dual_num]CH[chan_num]	—	SERDES High-Speed Inputs Termination Voltage Supplies, dual_num = [0, 1], chan_num = [0, 1]. These pins should be powered to 1.1 V on ECP5, or 1.2 V on ECP5-5G.
VCCHTX_D[dual_num]CH[chan_num]	—	SERDES High-Speed Outputs Buffer Voltage Supplies, dual_num = [0, 1], chan_num = [0, 1]. These pins should be powered to 1.1 V on ECP5, or 1.2 V on ECP5-5G.

Notes:

1. When placing switching I/Os around these critical pins that are designed to supply the device with the proper reference or supply voltage, care must be given.
2. These pins are dedicated inputs or can be used as general purpose I/O.
3. m defines the associated channel in the quad.

Supplemental Information

For Further Information

A variety of technical notes for the ECP5/ECP5-5G family are available.

- High-Speed PCB Design Considerations (TN1033)
- Transmission of High-Speed Serial Signals Over Common Cable Media (TN1066)
- PCB Layout Recommendations for BGA Packages (TN1074)
- Minimizing System Interruption During Configuration Using TransFR Technology (TN1087)
- Electrical Recommendations for Lattice SERDES (FPGA-TN-02077)
- LatticeECP3, ECP-5 and ECP5-5G Soft Error Detection (SED)/Correction (SEC) Usage Guide (TN1184)
- Using TraceID (TN1207)
- Sub-LVDS Signaling Using Lattice Devices (TN1210)
- Advanced Security Encryption Key Programming Guide for ECP5, ECP5-5G, LatticeECP3, and LatticeECP2/MS Devices (TN1215)
- LatticeECP3, LatticeECP2/M, ECP5 and ECP5-5G Dual Boot and Multiple Boot Feature (TN1216)
- ECP5 and ECP5-5G sysCONFIG Usage Guide (TN1260)
- ECP5 and ECP5-5G SERDES/PCS Usage Guide (TN1261)
- ECP5 and ECP5-5G sysIO Usage Guide (TN1262)
- ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide (TN1263)
- ECP5 and ECP5-5G Memory Usage Guide (TN1264)
- ECP5 and ECP5-5G High-Speed I/O Interface (TN1265)
- Power Consumption and Management for ECP5 and ECP5-5G Devices (TN1266)
- ECP5 and ECP5-5G sysDSP Usage Guide (TN1267)
- ECP5 and ECP5-5G Hardware Checklist (FPGA-TN-02038)
- Solder Reflow Guide for Surface Mount Devices (FPGA-TN-02041)
- ECP5 and ECP5-5G PCI Express Soft IP Ease of Use Guidelines (FPGA-TN-02045)
- Programming External SPI Flash through JTAG for ECP5/ECP5-5G (FPGA-TN-02050)
- Adding Scalable Power and Thermal Management to ECP5 Using L-ASC10 (AN6095)

For further information on interface standards refer to the following websites:

- JEDEC Standards (LVTTL, LVCMOS, SSTL): www.jedec.org
- PCI: www.pcisig.com